Simple and rapid preparation of CuO film using SILAR process for application as hole-transporting layer in p-i-n perovskite solar cell

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1. Introduction

Perovskite solar cells (PSCs) are the most popular emerging solar cell in research and commerce due to their unique properties. PSCs not only reach a high power conversion efficiency (PCE) in short research durations or in large scale fabrication, but also have re-productivity [1-6]. This advantage is a challenge for commercial and sustainable consumption. The original structure of PSCs was well-presented as n-i-p PSCs including mesoscopic and planar structures [7-10] which were fabricated as a sequential deposition layer by layer of an n-type semiconductor as an electron transporting layer (ETL), perovskite (PS), and a p-type semiconductor as a hole-transporting layer (HTL), respectively [11]. Popular ETLs such as TiO2 and ZnO have limited electron transport in PSCs because they have relative low mobility compared with PSs [8,12]. The effect of low mobility leads to an imbalance of electron-hole transportation and results in the accumulation of charge which can be detected from the hysteresis effect [13]. To solve the problem, high quality films have been used with several techniques such as interface engineering modification [14], additive modification [15-16], heat treatment [17], surface treatment [18-19] and chemical control [20]. These methods resulted in successful, enhanced PCE, however, some unexpected results were found such as unstable PCE, inappropriate required energy, and a relatively high expense. One effective method was developed by inverting the PSC structure from n-i-p to be p-i-n PSCs, and the p-i-n PSCs showed
better carrier transport efficiency than the other form. The p-i-n structure can be demonstrated by sequential deposition step by step of HTL, PS, and ETL, respectively [13,21]. However, most of the excellent HTLs such as PEDOT:PSS, P3HT, and spiro-OMeTAD are expensive [22]. Thus, several intrinsic p-type semiconductors were investigated as alternative HTLs such as NiO, CuSCN [21], CuO, [23-24], Cu2O, and CuO [25-26]. Among these, copper oxide groups (CuOx, Cu2O, CuO) should be considered as challenging materials because they have not only high hole mobility, but also have energy band level matching with PSs including CH3NH3PbI3, CH3NH3PbBr3, and CH3NH3SnI3 [27]. Moreover, they can be prepared using simple methods such as electrodeposition [28], spin-coating process [23-24], solution process [29], and the successive ionic layer adsorption and reaction (SILAR) method [30-31]. Several reports presented preparations of copper oxide using different methods for p-i-n perovskite solar cell application. For examples, CuOx films prepared by simple spin-coating process were applied as an HTL in p-i-n PSCs [23-24] resulting in enhanced PSC performance with good stability. The charge carrier separation rate gain increased the short-circuit current density (Jsc) due to the unique high work function of CuOx films. Nevertheless, the internal recombination was reduced to increase the open-circuit voltage (Voc) because the large grain size formation of perovskite films was supported by hydrophobic CuOx films. Similar to the CuOx films, Cu2O films prepared using electrodeposition were demonstrated as an HTL in PSCs [28]. It was found that the Cu2O films produced homogenous compact films with a large grain size and were pin-hole free. The Cu2O acted as growing sites for perovskite formation and resulted in PCE enhancement. Guo et al. (2017) [26] prepared Cu2O and CuO films using magnetron sputtering for HTL application in PSCs, and they suggested a low temperature process for PSC fabrication. Yu et al. (2016) [32] found that thickness and the properties of Cu2O films prepared using thermal oxidation were effective factors to enhance PSC performance. Zuo and Dind, (2015) [25] reported a simple spin-coating process of Cu2O and CuO films for HTL applied as HTLs in PSCs with high external quantum efficiency. A demonstration of Cu2O film preparation with a very simple SILAR method for PSC application was presented by Chatterjee and Pal (2016) [31]. PSC performance was enhanced because appropriate band alignment between the interfaces of Cu2O/CH3NH3PbI3/PCBM was achieved. The alignment is believed to improve the internal charge behavior which was reflected in the reduced series resistance (Rss) and the increased shunt resistance (Rsh).

From the literatures, the preparation of Cu2O films has been successfully reported for p-i-n PSC application due to low preparation temperature requirement. However, the Cu2O phase might not be stable for long term use in a high temperature environment while the CuO phase produces more stable materials. CuO films, thus, can be a challenging material in PSCs in a brutal environment. Moreover, an application of CuO films prepared by the SILAR method as an HTL in PSCs has been underreported. This is the first study applying SILAR processed CuO films as an HTL in p-i-n PSC. The films were prepared with different SILAR processed cycles, and characterized using various techniques. After each film was obtained, it was used as an HTL for p-i-n PSC application. The PSC performance was carried out under standard conditions. The results revealed a successful demonstration of the SILAR processed CuO films for application as an HTL in p-i-n PSC.

2. Materials and methods

2.1 Copper oxide film preparation

Before preparing CuO films, F:SnO2 (FTO) substrate was patterned using Zn metal and a mixed solution of HCl:deionized (DI) water (1/1, v/v). Then the substrate was moved to an ultrasonic bath and cleaned using detergent, DI water, acetone, and isopropanol, respectively, for 15 min each, and finally dried with flowing N2. A copper precursor was prepared by dissolving 0.1 M Cu(CO2CH3)2·H2O into distilled water, adding with NH4OH solution (25 vol.%) to be complex, and stirring for 1 h at room temperature. The H2O2 solution used as an oxidizer was prepared by mixing H2O2 solution (1 vol.%) into methanol. CuO films were prepared using a SILAR method [33]. The substrate was vertically dipped into the copper precursor, and held for 30 s to adsorb copper ions. After the adsorption process, the substrate was moved and dipped into methanol to remove aggregate ions for 30 s, and then dried for several seconds. The substrate was then dipped into the H2O2 solution to oxidize the adsorbed copper ions for 30 s. After the oxidation process, the substrate was dipped into methanol to remove any excess residual, and dried to complete a precursor
film for one cycle of the SILAR process. For additional cycle preparation, the process was sequentially repeated. Finally, the precursor film was annealed at 450°C for 1 h to form CuO films for using as an HTL in p-i-n PSC [30].

2.2 Perovskite solar cell fabrication

Starting solutions consisting of PbI₂, CH₃NH₃I, and PCBM were separately prepared. The PbI₂ solution was prepared by dissolving 1 M PbI₂ into DMF and stirring at 70°C, and the PbI₂ solution is maintained under stirring condition at 60°C to avoid crystallization. The CH₃NH₃I was prepared by dissolving 50 mg·ml⁻¹ into isopropanol and stirring at room temperature. The PCBM solution was prepared by dissolving 30 mg·ml⁻¹ PCBM into chlorobenzene and stirring at room temperature. For the perovskite solar cell fabrication, the CuO films were transferred into a grove box under a flowing N₂ atmosphere to maintain a low relative humidity below 35%. Organic-inorganic perovskite films, CH₃NH₃PbI₃, were prepared onto the top of CuO films using a two-step spin-coating deposition process according to previous work [34]. Briefly, the CuO films were pre-heated at 70°C for 15 min before the spin-coating process. Then, the PbI₂ solution was spin-coated onto the CuO films at 3000 rpm for 30 s, and immediately heated at 70°C for 15 min to form PbI₂ films (yellow films can be observed). After cooling down to room temperature, the CH₃NH₃I solution was spin-coated onto the PbI₂ films at 2000 rpm for 30 s and then heated at 100°C for 2 h to convert the PbI₂ films to be CH₃NH₃PbI₃ perovskite films. After the CH₃NH₃PbI₃ films cooled down to room temperature, the PCBM solution was spin-coated onto the CH₃NH₃PbI₃ films to be ETL. Finally, an Ag electrode was deposited onto the PCBM films using thermal evaporation.

2.3 Characterization

Field emission scanning electron microscopy (FE-SEM, JEOL JSM-6335F), operating at a voltage of 15.0 kV, was used to observe morphology. Energy X-ray dispersive spectroscopy was used to detect chemical elements. Ultraviolet-visible-near infrared (UV-Vis-NIR) spectroscopy was used to investigate optical transmission. Atomic force microscopy (AFM) was used to analyze topology, surface roughness, and thickness. Current density-voltage was measured with a photo mask active area of 0.04 cm² to evaluate photovoltaic performance, under standard solar illumination of 100 mW/cm² (AM1.5). Open-circuit voltage decay (OCVD) was performed to determine charge dynamics.

3. Results

Morphology of the copper oxide film prepared on FTO substrates using the SILAR process for different cycles of 1, 3, and 5 were shown in Figure 1. For the 1 cycle, numerous small dots of CuO were found over the FTO substrate and appeared as seed attachment. When the SILAR cycle was increased up to 3 and 5 cycles, the CuO film showed better coverage over the FTO surface according to the change in morphology. It should be note that the surface morphology could not be made smooth under any of these conditions because film crystallization could not be totally controlled. To gain insight of CuO film topology, the AFM image was observed to investigate the surface change (Figure 1(d-f)). The change of surfaces was found for different number of SILAR cycles. This might be due to different reaction to form CuO for repeating adsorption and reaction processes. For roughness analysis, average roughness (Rₐ) was measured as 9.517, 13.183 and 10.099 nm for SILAR cycles of 1, 3, and 5 cycles, respectively. However, the results showed insignificant change in roughness or surface morphology. The copper oxide film thickness was measured using mapping AFM mode, and it was calculated as 25.71, 47.35 and 66.52 nm for SILAR cycles of 1, 3, and 5, respectively.

To examine the chemical composition of the CuO films, EDS of the film with different cycles was detected as shown in Figure 2. The Cu element cannot be detected with 1 cycle which can be explained because too little CuO is formed, which agreed with the morphological image. To classify the structural type of CuO films, the diffraction peaks were carried out using XRD as shown in Figure 3. It was found that the peaks of FTO substrate and FTO/CuO films were not much difference. The indifferent observed XRD peaks from both of samples could be due to ultrathin CuO film formation. The unclear XRD peaks resulted that CuO films cannot be clearly interpreted. Thus, optical micrograph was investigated as shown in the inset figure of Figure 3. The micrograph showed that film color were difference between FTO and FTO/CuO films. Dark-brown was and white-blue
were observed for the FTO and FTO/CuO, respectively. Therefore, it could be assumed that CuO films were formed according to the dark-brown in case of FTO/CuO films.

Optical transmission of the film was measured using UV-Vis-NIR as shown in Figure 4(a). The average transmission in the visible region was calculated as 98.07%, 97.02%, and 93.34% for 1, 3, and 5 cycles, respectively. In addition, the optical band gap energy ($E_g$) can be estimated from the transmission for direct band gap materials according to the relation [31]:

$$\alpha h\nu = A(h\nu - E_g)$$  \hspace{1cm} (1)

From the relation, the plot of $(\alpha h\nu)^2$ versus $h\nu$ is shown in Figure 4(b). The linear part was fitted to obtain $E_g$ with a value of 1.94, 1.93, and 1.91 eV for 1, 3, and 5 cycles, respectively.

![Figure 1. SEM images and AFM images of CuO film prepared on FTO substrate with different number of cycles: (a,d) 1, (b,e) 3, and (c,f) 5.](image)

![Figure 2. Chemical elements of CuO films prepared on FTO substrate with different number of cycles: (a) 1, (b) 3, and (c) 5.](image)

![Figure 3. XRD patterns of FTO substrate and FTO/CuO films.](image)
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Figure 4. (a) Optical transmittance; and (b) optical band gap energy of CuO films prepared on FTO substrate for different cycles.

The CuO films were used as HTMs for p-i-n perovskite solar cells, and their performance was measured. Figure 5 shows the current density (J) versus the voltage (V) of the measured photovoltaic performance of the PSC fabricated using the CuO films. It was found that Jsc slightly increased with increasing cycles. The increase in Jsc indicates an improvement of charge collection for large cycles. The Voc increased and reached a maximum with 3 SILAR processed cycles.

From the J-V curve, photovoltaic parameters were calculated and listed in Table 1. Jsc slightly increased correlating to the SILAR cycles, while the FF decreased. This effect might be described according to the relation:

$$ FF = \frac{J_{\text{max}} V_{\text{max}}}{J_{\text{sc}} V_{\text{oc}}} $$

Where Jmax and Vmax are maximal J and maximal V, respectively. The decrease in FF might caused by a small change rate of maximum power (J_{sc}V_{oc}) compared with the ideal power (J_{max}V_{max}). This behavior was caused by the decreased shunt resistance (Rsh) of 307.28, 281.66 and 152.44 Ω for 1, 3 and 5 cycles. In addition, an occurrence of Voc decrement for 5 cycles could be attributed to higher recombination rate of generated electron due to interfacial defect between CuO films and perovskite films.

Table 1. Photovoltaic parameters of DSSC fabricated with CuO films using different numbers of cycles.

<table>
<thead>
<tr>
<th>Number of SILAR cycles</th>
<th>Jsc (mA/cm²)</th>
<th>Voc (V)</th>
<th>FF</th>
<th>PCE (%)</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>3.97</td>
<td>0.57</td>
<td>0.44</td>
<td>1.00</td>
</tr>
<tr>
<td>3</td>
<td>4.71</td>
<td>0.65</td>
<td>0.39</td>
<td>1.20</td>
</tr>
<tr>
<td>5</td>
<td>5.60</td>
<td>0.50</td>
<td>0.36</td>
<td>1.00</td>
</tr>
</tbody>
</table>

To evaluate the benefits of the CuO films for p-i-n PSC application, the device fabricated with 3 SILAR processed CuO films was selected as the optimized device compared with PEDOT:PSS as shown in Figure 6. The photovoltaic parameters of the PEDOT:PSS based device for Jsc, Voc, fill factor (FF), and PCE were 7.31 mA/cm², 0.75 V, 0.52, and 2.82%, respectively.

To investigate the behavior, morphology of CH3NH3PbI3 perovskite films coated onto CuO films and PEDOT:PSS films were examined as shown in Figure 7. Unfortunately, perovskite films showed an incomplete formation when coated onto CuO films. The perovskite films revealed a combination of compact and porous zones, while better film formation was observed with only the compact zone when it was coated onto PEDOT: PSS.
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Figure 6. Current density - voltage characteristics under standard illumination of p-i-n perovskite solar cell fabricated with PEDOT:PSS and CuO films.

Figure 7. Morphology of perovskite films coated onto (a) FTO/CuO and (b) FTO/PEDOT:PSS.

Due to the porous perovskite film formation, direct contact between the HTMs and ETMs might have occurred. This defect causes a carrier loss in p-i-n PSCs due to a recombination effect [18], which can be interpreted from the higher current density under the dark condition for CuO films as shown in Figure 8. During electron-hole pair generation, electrons and holes are injected and transported in ETMs and HTMs, respectively. They might be recombined due to direct HTM-ETM contact, leading to a carrier loss. Thus, this effect is believed to be a major factor in reducing p-i-n PSC performance.

Figure 8. Current density - voltage characteristics measured under dark conditions.

4. Discussion

The seed attachment for 1 cycle can be explained by the lack of copper ions due to the low cycle preparation for CuO film formation [35]. However, the CuO films showed better coverage over the FTO substrate after number of cycles increased up to 3 and 5 cycles. This can be attributed to the filling of CuO at void positions to form a full coverage film after more cycles of SILAR process, which was agreed with the AFM results. Moreover, the results were correlated to the increasing appearance of Cu element. The XRD peaks of CuO cannot observe for prepared CuO films because the CuO might be very thin. The thin films could be reflected from high transmittance above 90% for all conditions. However, from the EDS results and the high annealing temperature, it could assume that the prepared films are CuO [30, 36-38].

For PSC application, the J sc slightly increased with increasing cycles due to better coverage of the films over the substrate surface. Moreover, V oc could be attributed an optimized value for 3 SILAR processed cycles. The decreased of FF was found opposite with increase of Jsc can be interpreted that maximum power is maintained or small changed. From the J-V curve, photovoltaic parameters were calculated and listed in Table 1. J sc slightly increased correlating to the SILAR cycles, while the FF decreased. V oc increased and reached maximum for 3 cycles, similar to PCE. Then, the PSC
fabricated with 3 cycles of CuO films was compared with PEDOT:PSS. The PSC fabricated with CuO films showed lower photovoltaic parameters than PEDOT:PSS because it revealed the porous perovskite film formation. Therefore, the results clearly suggested that the low performance in a p-i-n perovskite solar cell was due to porous perovskite film formation as seen from lost of the dark current. The formation with pore structures could reduce HTMs/PSS/ETMs interfacial contact to form a p-i-n junction as the well known pinhole effect [16,39-40]. This work, however, demonstrated the ability of SILAR processed CuO films for applying as alternative HTMs in p-i-n PSC even through the films exhibited comparatively low performance. Note that for the p-i-n PSC performance improvement, the complete coverage of perovskite films on CuO films prepared using SILAR method should be further investigated. Different but efficient approaches could be considered such as control of film growth, doping with materials, surface treatment with solvent or vapor, and improved hydrophobic/hydrophilic property [41].

5. Conclusions

A demonstration of SILAR processed CuO films applied as a low cost hole-transporting material in a p-i-n perovskite solar cell was reported for the first time. The CuO films were prepared using SILAR method. The films had full coverage over substrate when the number of SILAR cycles increased; however, the open pores of perovskite films were still evident after deposition over the CuO films. This effect caused low levels of performance in p-i-n perovskite solar cell application compared with the commercial PEDOT:PSS hole-transporting material. However, the SILAR processed CuO films were shown to be suitable for use as alternative hole-transporting materials with a low fabrication cost for p-i-n perovskite solar cell application. To enhance device performance, the CuO films could be further investigated using various methods.

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